

Search Notes

Application/Control No.

10/693,151

Examiner

/BINH K. TIEU/

Applicant(s)/Patent under
Reexamination

HAN, JOHN MING-CHUAN

Art Unit

2614

SEARCHED

Class	Subclass	Date	Examiner
379	111	12/5/2007	BKT
	114.01		
	114.05		
	121.02		
	121.04		
	114.27		
	221.13		
↓	289		
455	405-408	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST DATABASES SEARCH	12/3/2007	BKT
WEST DATABASES SEARCH	12/5/2007	BKT